

In the Abstract:

Integrated test circuit arrangement and test method

~~An explanation is given, inter alia, of a test circuit arrangement (10) containing both integrated test structures (T1 to T5) and an integrated heating element, an integrated supply unit (40) and integrated detection unit (42). Tests of a multiplicity of test structures (T1 to T5) can be implemented in a simple manner with the aid of this circuit arrangement (10).~~

(Figure 1)

An integrated test circuit arrangement is provided that contains integrated test structures, at least one integrated heating element, an integrated detection unit, an integrated supply unit, and a control unit. The integrated detection unit detects at least one physical property for each of the test structures. The integrated supply unit supplies each of the test structures with a current or a voltage in switchable fashion independently of one another. The control unit is connected to outputs of the detection unit on an input side and controls the supply unit dependent on the detection results.